

<b>Notice of References Cited</b>	Application/Control No. 09/523,990	Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Daniel I. Walsh	Art Unit 2876	Page 1 of 5

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<b>Notice of References Cited</b>	Application/Control No. 09/523,990		Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Daniel I. Walsh		Art Unit 2876	Page 2 of 5

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<b>Notice of References Cited</b>	Application/Control No. 09/523,990	Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Daniel I. Walsh	Art Unit 2876	Page 3 of 5

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<b>Notice of References Cited</b>	Application/Control No. 09/523,990	Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Daniel I. Walsh	Art Unit 2876	Page 4 of 5

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	Examiner Daniel I. Walsh	Art Unit 2876	Page 5 of 5

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